

ABSTRACT

An LSI test equipment can acquire output data of an LSI as a device under test by a clock signal output from the LSI to be measured and acquire measurement data synchronously with the output data having jitter. The LSI test equipment (10) includes a clock side time interpolator (20) for acquiring the clock output from the LSI (1) to be measured by a plurality of strobes having a predetermined timing interval and outputting it as encoded level data of time series, a data side time interpolator (20) for acquiring the output data output from the LSI (1) to be measured by a plurality of strobes having a predetermined timing interval and outputting it as level data of time series, and a selector (30) for receiving the level data from both of the time interpolators, selecting output data at the clock edge timing, and outputting it as data to be measured.